

FEATURES/BENEFITS

- 5V tolerant inputs and outputs
- Industry standard pinouts
- 10 μ A I_{CCQ} quiescent power supply current
- Hot insertable
- 2.0V-3.6V V_{CC} supply operation
- \pm 24mA balanced output drive
- Meets or exceeds JEDEC Standard 36 specifications
- Power down high impedance inputs and outputs
- C speed performance: t_{PD} = 4.2ns
- Input hysteresis for noise immunity
- Multiple power and ground pins for low noise
- Operating temperature range:
 -40°C to +85°C
- Latch-up performance exceeds 500mA
- ESD performance:
 Human body model > 2000V
 Machine model > 200V
- Packages available:
 48-pin TSSOP
 48-pin SSOP

DESCRIPTION

The LCX16373 is a 16-bit buffered latch with three-state outputs that is ideal for driving address and data buses. The output enable and latch enable controls are organized to operate this device as two 8-bit latches, or one 16-bit latch. Easy board layout is facilitated by the use of flow-through pinouts and byte enable controls provide architectural flexibility for system designers. The 3.3V LCX family features low power, low switching noise, and fast switching speeds for low power portable applications as well as high-end advanced workstation applications. 5V tolerant inputs and outputs allow this LCX product to be used in mixed 5V and 3.3V applications. To accommodate hot-plug or live insertion applications, this product is designed not to load an active bus when V_{CC} is removed.

Figure 1. Functional Block Diagram

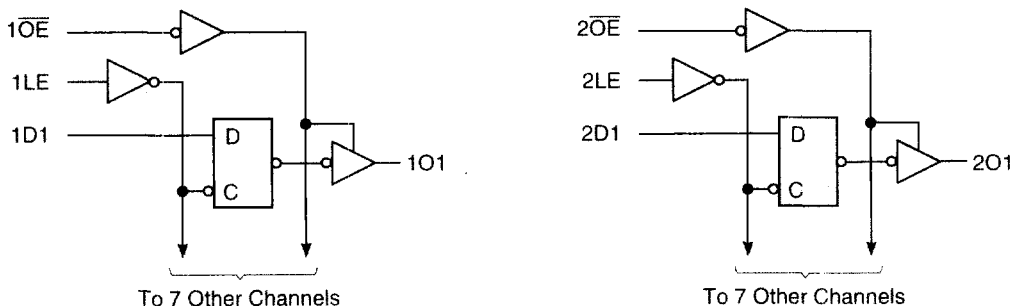
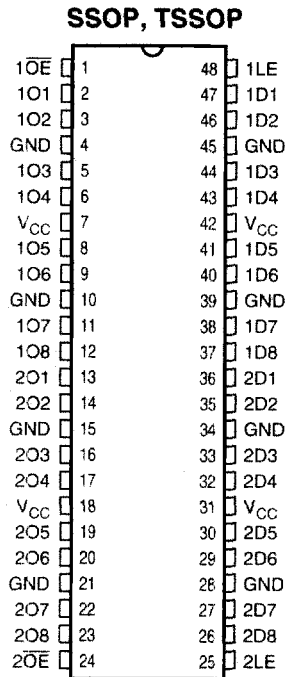


Figure 2. Pin Configuration (All Pins Top View)



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Table 1. Pin Description

Name	I/O	Description
xDx	I	Data Inputs
xOx	O	Data Outputs
xLE	I	Latch Enable
xOE	I	Output Enable

Table 2. Function Table

\overline{xOE}	Inputs xLE	xDx	Internal Q Value	Outputs xOx	Function
H	X	X	X	Hi-Z	Disable Outputs
L	L	X	H	H	Enable Outputs
L	L	X	L	L	
L	H	L	L	L	Pass Inputs
L	H	H	H	H	
L	L	X	Q	Q	Hold Prior Data

Table 3. Capacitance

Symbol	Pins	Typ	Unit	Conditions
C_{IN}	Input Capacitance	7.0	pF	$V_{IN} = 0V, V_{OUT} = 0V, f = 1MHz$
$C_{I/O}$	I/O Capacitance	8.0	pF	$V_{IN} = 0V, V_{OUT} = 0V, f = 1MHz$
C_{PD}	Power Dissipation Capacitance	20	pF	$V_{CC} = 3.3V, V_{IN} = 0$ or V_{CC} $f = 10MHz$

Note: Capacitance is characterized but not production tested.

Table 4. Absolute Maximum Ratings

Supply Voltage to Ground	-0.5V to +7.0V
DC Output Voltage V_{OUT}	
Outputs HIGH-Z	-0.5V to +7.0V
Outputs Active	-0.5V to $V_{CC} + 0.5V$
DC Input Voltage V_{IN}	-0.5V to 7.0V
DC Input Diode Current with $V_{IN} < 0$	-50mA
DC Output Diode Current	
$V_O < 0$	-50mA
$V_O > V_{CC}$	+50mA
DC Output Source/Sink Current (I_{OH}/I_{OL})	$\pm 50mA$
DC Supply Current per Supply Pin	$\pm 100mA$
DC Ground Current per Ground Pin	$\pm 100mA$
T_{STG} Storage Temperature	-65°C to +150°C

Note: Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to QSI devices that result in functional or reliability type failures.

Table 5. Recommended Operating Conditions

Symbol	Parameter	Min	Max	Unit
V_{CC}	Supply Voltage, Operating	2.0	3.6	V
	Supply Voltage, Data Retention	1.5	3.6	
V_{IN}	Input Voltage	0	5.5	V
V_{OUT}	Output Voltage in Active State	0	V_{CC}	V
V_{OUT}	Output Voltage in "OFF" State	0	5.5	V
I_{OH}/I_{OL}	Output Current $V_{CC} = 3.0 - 3.6V$ $V_{CC} = 2.7V$	—	± 24	mA
		—	± 12	
$\Delta t/\Delta v$	Input Transition Slew Rate	—	10	ns/V
T_A	Operating Free Air Temperature	-40	+85	°C

Table 6. DC Electrical Characteristics Over Operating Range

Industrial Temperature Range, $T_A = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$

Symbol	Parameter	Test Conditions	Min	Typ ⁽¹⁾	Max	Unit
V_{IH}	Input HIGH Voltage	Logic HIGH for All Inputs	2.0	—	—	V
V_{IL}	Input LOW Voltage	Logic LOW for All Inputs	—	—	0.8	V
V_{OH}	Output HIGH Voltage	$V_{CC} = 2.7\text{V}, I_{OH} = -100\mu\text{A}$ $V_{CC} = 2.7\text{V}, I_{OH} = -12\text{mA}$ $V_{CC} = 3.0\text{V}, I_{OH} = -18\text{mA}$ $V_{CC} = 3.0\text{V}, I_{OH} = -24\text{mA}$	$V_{CC}-0.2$ 2.2 2.4 2.2	—	—	V
V_{OL}	Output LOW Voltage	$V_{CC} = 2.7\text{V}, I_{OL} = 100\mu\text{A}$ $V_{CC} = 2.7\text{V}, I_{OL} = 12\text{mA}$ $V_{CC} = 3.0\text{V}, I_{OL} = 16\text{mA}$ $V_{CC} = 3.0\text{V}, I_{OL} = 24\text{mA}$	—	—	0.2 0.4 0.4 0.5	V
ΔV_T	Input Hysteresis ⁽²⁾	$V_{TLH} - V_{THL}$ for All Inputs	—	150	—	mV
I_I	Input Leakage Current	$V_I = 0\text{V}, V_I = 5.5\text{V}, V_{CC} = 3.6\text{V}$	—	—	± 1.0	μA
I_{OZ}	High-Z I/O Leakage	$V_O = 0\text{V}, V_O = 5.5\text{V}$ $V_I = V_{IH}$ or $V_{IL}, V_{CC} = 3.6\text{V}$	—	—	± 1.0	μA
I_{OS}	Short Circuit Current ^(2,3)	$V_{CC} = 3.6\text{V}, V_{OUT} = \text{GND}$	-60	—	-240	mA
I_{OFF}	Power Off Leakage	$V_{CC} = 0\text{V}, V_I$ or $V_O = 5.5\text{V}$	—	—	10	μA
V_{IK}	Input Clamp Voltage	$V_{CC} = 2.7\text{V}, I_{IN} = -18\text{mA}$	—	-0.7	-1.2	V

Notes:

1. Typical values indicate $V_{CC} = 3.3\text{V}$ and $T_A = 25^{\circ}\text{C}$.
2. These parameters are guaranteed by characterization, but not production tested.
3. Not more than one output should be tested at one time. Duration of test should not exceed one second.

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Table 7. Power Supply Characteristics

Symbol	Parameter	Test Conditions ⁽¹⁾	Typ ⁽²⁾	Max	Unit	
I_{CC}	Quiescent Power Supply Current	$V_{CC} = 3.6V$, Freq = 0 $V_{IN} = GND$ or V_{CC}	0.1	10	μA	
ΔI_{CC}	Supply Current per Input @ TTL HIGH ⁽³⁾	$V_{CC} = 3.6V$, $V_{IN} = V_{CC} - 0.6V$, Freq = 0	2.0	30	μA	
I_{CCD}	Supply Current per Input per MHz ⁽⁴⁾	$V_{CC} = 3.6V$, Outputs Open One Bit Toggling @ 50% Duty Cycle $x\overline{OE} = GND$	50	75	$\mu A / MHz$	
I_C	Total Power Supply Current ⁽⁶⁾	$V_{CC} = 3.6V$, Outputs Open One Bit Toggling @ 50% Duty Cycle $x\overline{OE} = GND$, $f = 10MHz$	$V_{IN} = V_{CC} - 0.6V$ $V_{IN} = GND$	0.5 ⁽⁵⁾	0.8 ⁽⁵⁾	mA
		$V_{CC} = 3.6V$, Outputs Open Sixteen Bits Toggling @ 50% Duty Cycle $x\overline{OE} = GND$, $f = 2.5MHz$	$V_{IN} = V_{CC} - 0.6V$ $V_{IN} = GND$	2.0 ⁽⁵⁾	3.3 ⁽⁵⁾	mA

Notes:

- For conditions shown as Min. or Max., use the appropriate values specified under Recommended Operating Conditions for applicable device type.
- Typical values are at $V_{CC} = 3.3V$, +25°C ambient.
- Per TTL driven input. All Other Inputs at V_{CC} or GND.
- This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
- Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed by design but not tested.
- $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$
 $I_C = I_{CCQ} + \Delta I_{CC} D_H N_T + I_{CCD} f N_O$
 I_{CCQ} = Quiescent Current (I_{CC1} , I_{CC2} , and I_{CCZ}).
 ΔI_{CC} = Power Supply Current for a TTL-High Input ($V_{IN} = V_{CC} - 0.6V$).
 D_H = Duty Cycle for TTL High Inputs.
 N_T = Number of TTL High Inputs.
 I_{CCD} = Dynamic Current Caused by an Input Transition Pair (HLH or LHL).
 f = Average Switching Frequency per Output.
 N_O = Number of Outputs Switching.

Table 8. Dynamic Switching Characteristics ⁽¹⁾

Symbol	Parameter	Conditions	V_{CC} (V)	$T_A = 25^\circ C$	
				Typical	Units
V_{OLP}	Quiet Output Dynamic Peak V_{OL}	$C_L = 50pF$, $V_{IH} = 3.3$, $V_{IL} = 0V$	3.3	0.8	V
V_{OLV}	Quiet Output Dynamic Peak V_{OL}	$C_L = 50pF$, $V_{IH} = 3.3$, $V_{IL} = 0V$	3.3	0.8	V

Note:

- Characterized but not production tested.

Table 9. Switching Characteristics Over Operating Range

Industrial Temperature Range, $T_A = 40^\circ\text{C}$ to $+85^\circ\text{C}$

$C_{\text{LOAD}} = 50\text{pF}$, $R_{\text{LOAD}} = 500\Omega$ unless otherwise noted.

Symbol	Description ⁽¹⁾	16373				16373C		Unit
		$V_{\text{CC}} = 3.3 \pm 0.3\text{V}$		$V_{\text{CC}} = 2.7\text{V}^{(2)}$		$V_{\text{CC}} = 3.3 \pm 0.3\text{V}$		
		Min	Max	Min	Max	Min	Max	
t_{PHL} t_{PLH}	Propagation Delay Di to xOx	1.5	5.4	1.5	5.9	1.5	4.2	ns
t_{PHL} t_{PLH}	Propagation Delay xLE to xOx	2.0	5.5	2.0	6.4	2.0	5.5	ns
t_{PZH} t_{PZL}	Output Enable Time xOE to xOx	1.5	6.1	1.5	6.5	1.5	5.5	ns
t_{PHZ} t_{PLZ}	Output Disable Time ⁽²⁾ xOE to xOx	1.5	6.0	1.5	6.3	1.5	5.0	ns
t_{S}	Data Setup Time xDx to xLE HIGH to LOW	2.5	—	2.5	—	2.0	—	ns
t_{H}	Data Hold Time xDx to xLE HIGH to LOW	1.5	—	1.5	—	1.5	—	ns
t_{W}	LE Pulse Width ⁽²⁾ HIGH	3.0	—	3.0	—	3.0	—	ns
$t_{\text{SK(O)}}$	Output Skew ⁽³⁾	—	0.5	—	—	—	0.5	ns

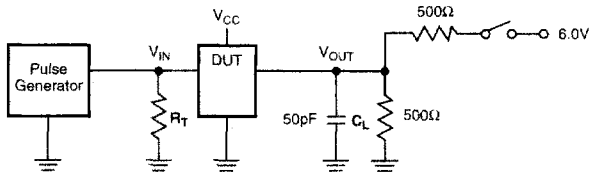
Notes:

1. Minimums guaranteed but not tested on propagation delays. See Test Circuit and Waveforms.
2. Guaranteed by characterization.
3. Skew between any two outputs of the same package switching in the same direction.
This parameter is guaranteed by characterization but not production tested.

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TEST CIRCUIT AND WAVEFORMS

Figure 3. Test Circuit



SWITCH POSITION

Test	Switch
Open Drain	
Disable LOW	6V
Enable LOW	
Disable HIGH	GND
Enable HIGH	
All Other Inputs	Open

DEFINITIONS:

CL = Load capacitance: includes jig and probe capacitance.

RT = Termination resistance: should be equal to ZOUT of the Pulse generator.

Figure 4. Setup, Hold, and Release Timing

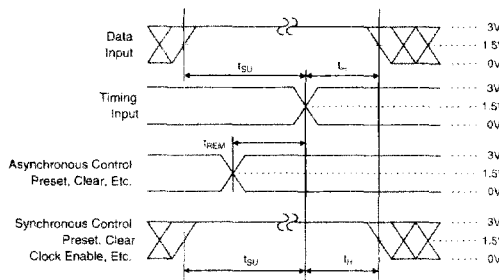


Figure 6. Pulse Width

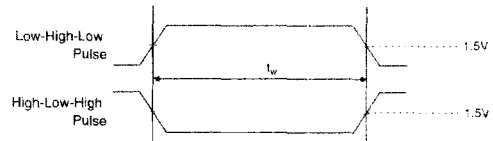


Figure 5. Enable and Disable Timing

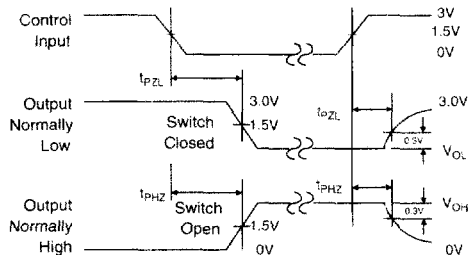
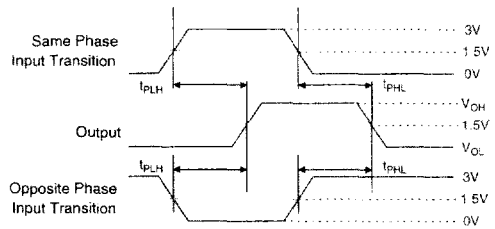


Figure 7. Propagation Delay



Notes:

1. Input Control Enable = LOW and input Control Disable = HIGH.
2. Pulse Generator for All Pulses: Rate ≤ 1.0MHz; ZOUT ≤ 50Ω; tF, tR ≤ 2.5ns.